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Opportunistic Networks

Guest Editor:

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Deadline for manuscript submissions:

closed (30 November 2020)

Message from the Guest Editor

This Special Issue encourages submissions not only related to recent research developments on opportunistic networks but also articles describing experimental results and mobility data obtained from real scenarios.

Keywords

- Architecture for OppNets
- Unicast and multicast routing
- Simulation and modeling of OppNets
- Mobility analysis and models for OppNets
- Security issues in OppNets
- New applications and services based on OppNets
- Opportunistic mobile social networks
- Mobile crowdsensing and urban sensing
- Vehicular social networks (VSN)

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Message from the Editor-in-Chief

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